Search Notes



| Аp | pli | cat | ion | Co | ntrol | No |
|----|-----|-----|-----|----|-------|----|
| | | | | | | |

10717741

Applicant(s)/Patent Under Reexamination

CONROY ET AL.

Examiner

Keefer, Michael E

Art Unit

2454

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|-------------------------|-----------|----------|
| 709 | 206 (updated 2/26/2009) | 6/28/2007 | MEK |

SEARCH NOTES

| Search Notes | Date | Examiner |
|---|-----------|----------|
| EAST Search | 6/28/2007 | MEK |
| Google Search | 6/28/2007 | MEK |
| ACM Search | 6/29/2007 | MEK |
| IEEE Xplore Search | 6/29/2007 | MEK |
| EAST Search | 9/13/2008 | MEK |
| Consulted Primary Examiner Dustin Nguyen, Class 709 | 2/26/2009 | MEK |
| Consulted Examiner Hassan Phillips, Class 709 | 2/26/2009 | MEK |

INTERFERENCE SEARCH

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
| | | | |

U.S. Patent and Trademark Office Part of Paper No.: 20090226